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» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

Select Article Information

- ☐ 1. **Time-domain simulation of sampled weakly nonlinear systems using ana integration and orthogonal polynomial series [mixed-signal IC application]**
Martens, E.; Gielen, G.;
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2005 Page(s):120 - 125 Vol. 1
Digital Object Identifier 10.1109/DATE.2005.311
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- ☐ 2. **Design and analysis of power-CMOS-gate-based switched-capacitor boost inverter**
Yuen-Haw Chang;
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Volume 51, Issue 10, Oct. 2004 Page(s):1998 - 2016
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- ☐ 3. **Passive reduction algorithm for RLC interconnect circuits with embedded systems (PRESS)**
Saraswat, D.; Achar, R.; Nakhla, M.S.;
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- ☐ 4. **Study of "tanh" ideal and lossy ELIN integrators**
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Volume 2, 13-16 May 2004 Page(s):177 - 183 vol.2
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- ☐ 5. **Cost-efficient block verification for a UMTS up-link chip-rate coprocessor**
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- ☐ 6. **A new nonlinear transient modelling technique for high-speed integrated applications based on state-space dynamic neural network**
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- ☐ 7. **Fast and accurate identifying subcircuits using an optimization based technique**
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- ☐ 8. **Implicit resolution of the Chapman-Kolmogorov equations for sequential application in power estimation**
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- ☐ 10. **Model checking algorithms for analog verification**
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- ☐ 11. **Guaranteed passive balancing transformations for model order reduction**
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- ☐ **21. A guaranteed stable order reduction algorithm for packaging and interconnect**
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